

Title (en)
OSCILLOSCOPE PROBE

Title (de)
OSZILLOSKOP-TASTKOPF

Title (fr)
SONDE D'OSCILLOSCOPE

Publication
EP 2052263 A1 20090429 (DE)

Application
EP 07765099 A 20070705

Priority
• EP 2007005981 W 20070705
• DE 102006038027 A 20060814
• DE 102006052748 A 20061108

Abstract (en)
[origin: WO2008019732A1] Disclosed is an oscilloscope probe comprising a transistor amplifier (3) which is mounted on a semiconductor substrate (2) as integrated circuitry. In said oscilloscope probe, at least part of the input voltage divider (4) is also mounted on the semiconductor substrate (2) as integrated circuitry along with the amplifier (3).

IPC 8 full level
G01R 1/067 (2006.01); **G01R 1/20** (2006.01)

CPC (source: EP US)
G01R 1/203 (2013.01 - EP US); **G01R 1/06766** (2013.01 - EP US)

Citation (search report)
See references of WO 2008019732A1

Citation (examination)
• EP 0327078 A2 19890809 - TOSHIBA KK [JP]
• US 3441804 A 19690429 - KLEMMER JACK W
• US 5225776 A 19930706 - DOBOS LASZLO J [US], et al
• US 6373348 B1 20020416 - HAGERUP WILLIAM A [US]
• US 2002074319 A1 20020620 - WILBUR MARK STEVEN [US], et al

Designated contracting state (EPC)
DE FR GB

Designated extension state (EPC)
AL BA HR MK RS

DOCDB simple family (publication)
WO 2008019732 A1 20080221; DE 102006052748 A1 20080430; EP 2052263 A1 20090429; US 2010231199 A1 20100916;
US 8278953 B2 20121002

DOCDB simple family (application)
EP 2007005981 W 20070705; DE 102006052748 A 20061108; EP 07765099 A 20070705; US 29878907 A 20070705